

No.1437E

\_C3100

C MOS LSI 128K-BIT-CMOS MASK ROM

The LC3100 is a 128k-bit CMOS mask ROM that contains an interface connectable direct to the speech synthesizer LSI LC8100. With one piece of this mask ROM, approximately 100 seconds of speech synthesis can be attained. A selection of 8-bit, 4-bit, or single-bit output data is allowed by means of external control This mask ROM is also suited for use in applications other than speech synthesis.

### Features

· ROM capacity

Access time

· Cycle time

· Function

· Low power dissipation

· Current dissipation

Single +5V power supply

• Package

128k bits

6.9µsec typ (for operation at 800k#/z/typ.) 26. Ousec typ (for operation at 200kHz typ.) 8. lusec typ (for operation at 850kHz typ)

30.6usec typ (for operation at 200kHz typ.)

(1) Contains an interface to the LC8100 (speech synthesizer LSI)/

(2) Possible to select the bit length of output data

8-bit data 4-bit data Single-bit data

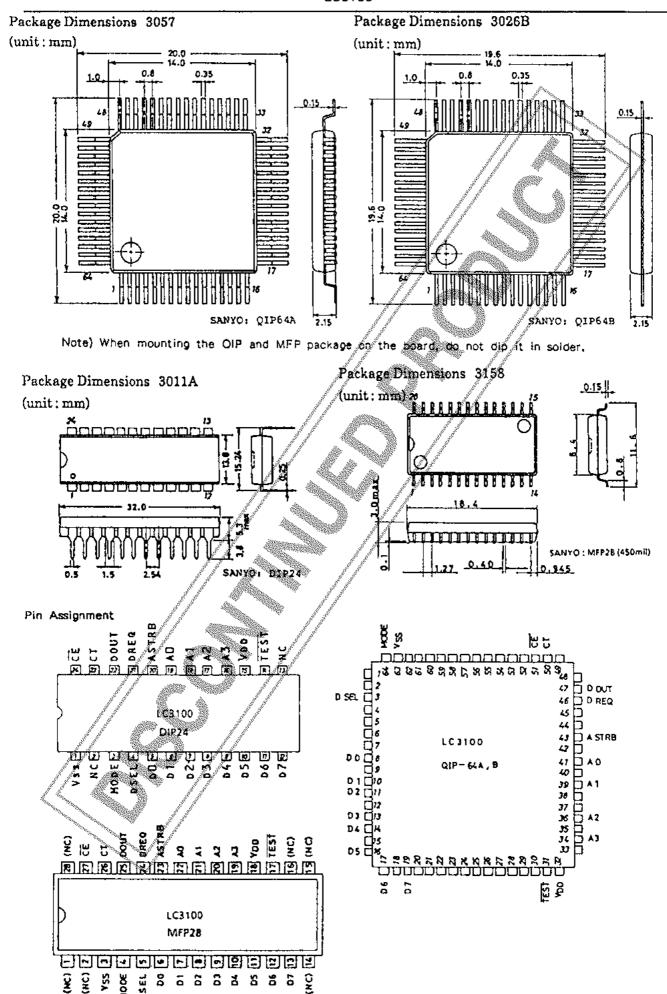
**CMOS** 

2mA max. (at operating mode) INA max. (at nonoperating mode) +4.5 to 6.5 V (supply voltage range) DIP24, QIP64A, QIP64B, MFP28

The application citizent diagrams and circuit constants herein are included as an example and provide no guarantee for designing

equitment to be mass-produced. The information herein is believed to be accurate and reliable. However, no responsibility is assumed, by SANYO for its use, nor talk and information herein is beginned by SANYO for its use, nor talk any information of parties which may result from its use.

Specifications and information herein are subject to change without notice.



### Equivalent Circuit Block Diagram

A0 to A3:

ASTRB:

18-bit address setting pins A0 to A3 strobe pin

DREQ:

ROM data request pin

DOUT:

ROM data serial output pin

CT:

Basic operation clock input pin

D0 to D7: MODE:

8-bit input/output pins DREQ pin input pulse count control pin

DSEL:

Output bit length select pin

ČE:

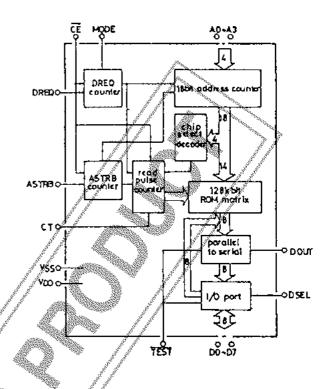
Power-down control pin

TEST:

Test pin

VDD.VSS:

Power supply pin



### Description of Operation of Internal Block

. ASTRB COUNTER:

Block which internally sets address information applied in 5 steps from

• 18-bit ADDRESS COUNTER: \* READ PULSE COUNTER:

. CHIP SELECT DECODER:

• 128k-bit ROM MATRIX:

• PARALLEL TO SERIAL:

• 1/0 PORT:

A0 to A3 pins.
Address counter organized with 18 bits.

Block which generates signal to operate address decoder, data selector.

Makes chip select signal with 234 to 217 bits of 18-bit address.

ROM matrix cell organized with 128k bits.

Shift register which serially outputs 8-bit parallel data to DOUT pin.

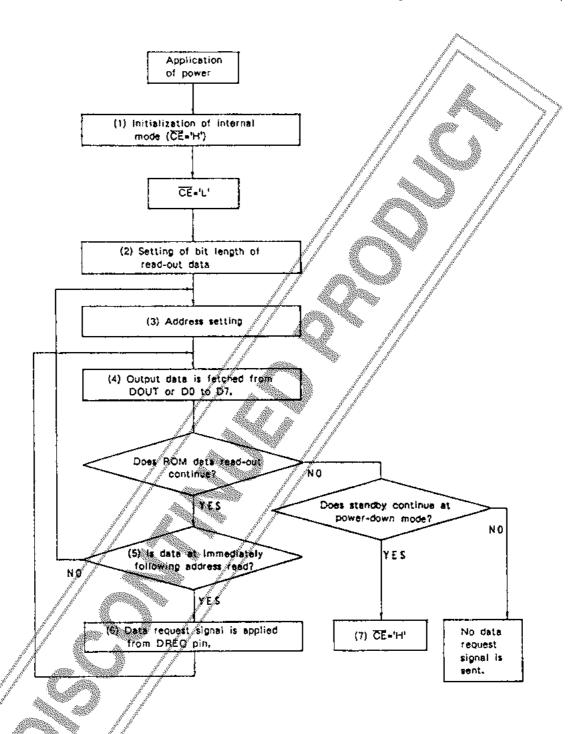
Selects input/output at D0 to D7 pins.

# Pin Description

Pin I	No. DIP28	Pin Name	Input/Output	Function
43	20	ASTRB	Input	Pin for inputting strobe signal which causes data  A0 to A3 to be latched at address setting mode.
46	21	DREQ	Input	ROM data request signal input pin.
47	22	TUOG	Output	Pin for outputting ROM data serially. When used in conjunction with the LC8100, this pin is connected to DIN pin of the LC8100.
50	23	ст	Input	Pin for inputting basic operation clock of ROM system. When used in conjunction with the EC8100, this pin is connected to CT pin of the LC8100.
51	24	CE	Input	Pin for controlling initialization of LSI system immediately after application of power and internal operation stop (power-down). For performing synthesization or ROM data read-out, set CE to 'L'.
63	1	∨ss	<u> </u>	Connected to OV of power supply.
32	15	VDD	-	Connected to +side of power supply.
64	3	MODE	input de la companya del companya de la companya del companya de la companya de l	Pin for controlling number of input pulses at DREO pin. When ROM data read-out is performed serially in bit units, set MODE to 'L'. When ROM data read-out is performed in units of 8 bits or 4 bits, set MODE to 'H'.
3	4	DSEL	Imput	Used when ROM data read-out is performed in units of 4 bits. When DSEL is set to 'H', 2 to 2 bits are output to D0 to D3 pins.
8 10 11 13 14 16 17	5 6 7 8 9 10 11	D0 D1 D2 D3 Q4 Q5 D6 D7	knout/output	Pins for outputting ROM data in units of 8 bits and inputting data in units of 8 bits.
31	14	TEST	Mput	LSI test pin. Open or connected to VDD.
34 36 39 41	16 17 18	A2 A2 A1 A0	Input	Pins for setting 18-bit address. At address setting mode, address information is input by 4 bits from high-order bit downward in 5 steps.

# ROM Data Read-out Procedure

The following flowchart shows the outline of read-out procedure. (1) to (7) give a more detailed description.



# (1) Initialization of internal mode

There are 4 counter blocks (ASTRB counter, 18-bit ADDRESS counter, READ PULSE counter, DREO counter) inside the LC3100. Since initialization is required immediately after application of power, apply one 'H' level pulse to CE pin. When CE is set to 'L' level, the power-down mode is released (refer to (6)) and it is possible to start read-out any time.

## (2) Setting of bit length of read-out data

For the bit length of ROM data output, a selection of 3 lengths is allowed: 8 bits, 4 bits, and a single bit. For controlling this selection, MODE, DSEL pins are used. The following Table shows 3 types of pin setting.

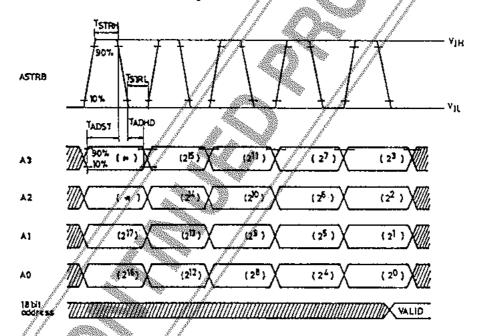
.. .......

MODE	L	Н
L	Single-bit length (speech synthesis)	8-bit or 4-bit length or 4-bit length (Note)
Н.		4-bit length (Note)

(Note) When DSEL is set to 'L', 2° to 2° bits are output at D0 to D3 pins.

### (3) Address setting

Apply 5 successive pulses to ASTRB pin. Synchronously with these pulses apply 18-bit address information to A0 to A3 pins from high-order bit downward by 4 bits in 5 steps. At this address setting mode DREQ pin must be set to 'L' ievel. Shown below is the timing.



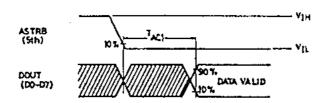
(Note) - "+" -don't care.

- "2" Binary number at the 7th bit to be set in address counter.
   For the numeric values of TSTRH, TSTRL, TADST, TADHS, refer to Electrical Characteristics.

# Start of read-out of set address data

Read-out of ROM data starts at the falling of the 5th ASTRB pulse or the first (MODE='H') or the 8th (MODE='L') DREC pulse, and when access time TAC1 has elapsed 2° bit is output at DOUT pin and 2° to 27 data are output at DO to D7 pins, (Refer to the following Timing Chart.)

Note) For the numeric value of TAC1, refer to Electrical Characteristics.



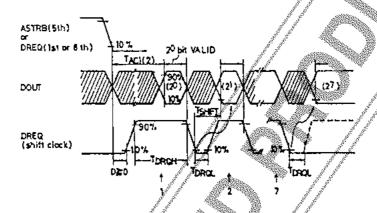
### (4) Fetching of output data

As shown above, whenever access time TAC1 has elapsed, data can be fetched from output ports DOUT or D0 to D7 pins. (Pin setting as shown in Table in (2) is required.)

Counting one byte in bit units from DOUT pin

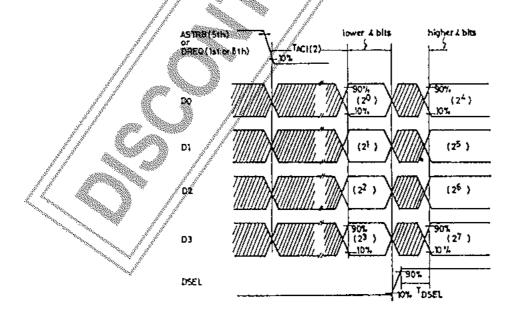
Count a single bit (2<sup>n</sup> bit) from DOUT pin. To count the following single bit (2<sup>n+1</sup> bit), apply a shift clock to DREQ pin. Shown below is Timing Chart,

For the numeric values of TAC1, TDRQH, TDRQL, TSHFT, refer to Electrical Characteristics.



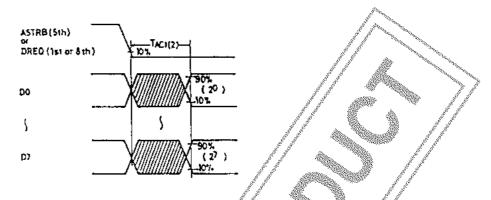
Counting one byte in units of 4 bits from D0 to D3 pins

In accordance with Table and (Note) in (2), one byte is fetched from D0 to D3 pins by 4 bits in 2 steps. Shown below is Timing Chart.

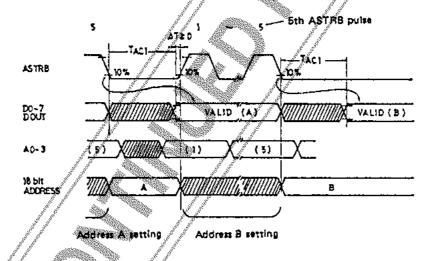


# Counting one byte in units of 8 bits from D0 to D7 pins

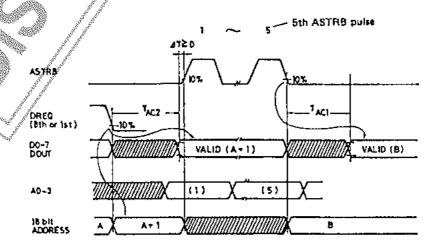
Eight bits are fetched from D0 to D7 pins. Shown below is Timing Chart.



- (5) Setting address again and counting data
  - (1) Timing for application of ASTRB pulse when address A is set and read out and then address B is set and read out.



(2) Timing for application of ASTRB pulse when data is read out by application of DREQ signal (refer to (6) below) and then address B is set and read out.



### (6) Request of ROM data at the following address

Falling of 8th DREQ pulse (MODE='L')

When the signal shown below is applied to the LSI, the LSI begins to read out data at the address immediately following the address at which preceding data is read out.

Falling of 1st DREQ pulse (MODE='H')

Shown below is Timing Chart.

ASTRB(5th) or DREQ(1st or 8th)

ADDRESS

DO-7

DOUT

DREQ

DREQ

POT.

8 pulses (MODE:L) or 1 pulse (MODE:H)

Note) Apply ROM data request signal after TCYCLE or more has elapsed. For the numeric value of TCYCLE, refer to Electrical Characteristics.

## (7) Power-down mode

When the input at CE pin is set to H level, the LC3100 enters power-down mode (each block inside the LSI stops its operation, with no unnecessary current dissipated.). At this mode, the LSI system becomes as follows and current dissipation is reduced.

- (1) Input at input ports (ASTRB, DREO, A0 to A3) is inhibited.
  (It should be noted that if input is floating, current dissipation increases.)
- (2) Both address decoder and data selector in 128k-bit ROM matrix stop their internal operation.
- (3) Output at 3-state output pins DOUT, D0 to D7 is floating or fixed. (The user can select either of the two. Refer to "User mask") When CE is set to 'H', in addition to reduction in current dissipation as mentioned above, 4 internal counters (ASTRB COUNTER, 18-BIT ADDRESS COUNTER, READ PULSE COUNTER, DREC COUNTER) are initialized in readiness for read-out after power-down mode release (CE='L').

#### User mask

## (1) CHIP SELECT DECODER

User mask option which makes LSi chip select signal (select, nonselect) with  $2^{14}$  to  $2^{17}$  bits of 18-bit addresses. Shown below is the output modes including  $\overline{CE}$  pin conditions.

	CE='L'	CE='H' (Power-bown)
Chip select	Data is output from DOUT, DO to D7 pins.	Data immediately before CE2'H' occurs is held and output. (Note)
Chip nonselect	Output at DOUT, D0 to D7 pins is brought to high impedance state.	Output at DOUT, DO to D7 pins is prought to high impedance state.

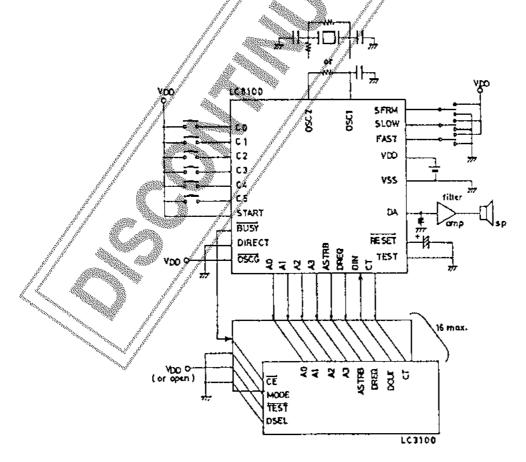
Note) in this case, the LSI only, having CHIP SELECT DECODER whose 21st to 217 bits are all 0, outputs data and all others are brought to high impedance state.

### (2) SW mask

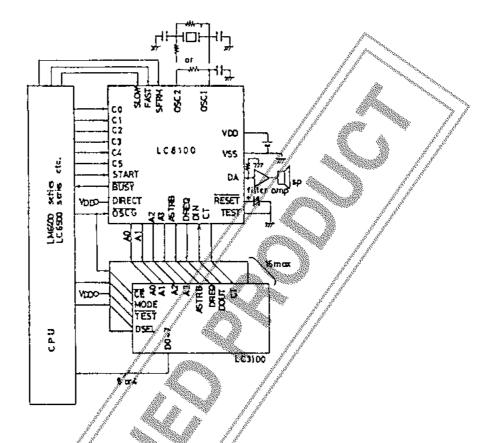
SW mask controls output at DOUT, D0 to D7 output pins in the following two ways at power-down mode. The user can select either of the two beforehand.

- (i) Output at DOUT, D0 to D7 pins is brought to high impedance state.
- (ii) Data immediately before power-down mode is held and output. (LSI only which has CHIP-SELECT DECODER whose 2<sup>14</sup> to 2<sup>17</sup> bits are all 0)

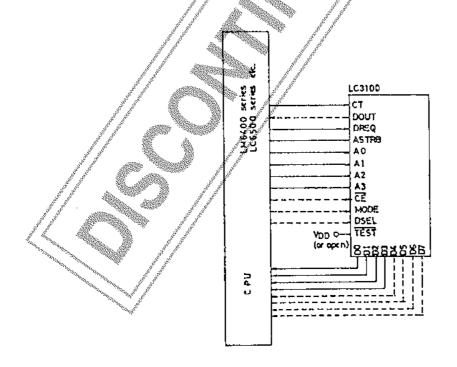
Sample Application Circuit (1) One word to one key correspondence



Sample Application Circuit (2) CPU control: Editing and synthesis with CPU



Sample Application Circuit (3) CPU control: Application other than speech synthesis

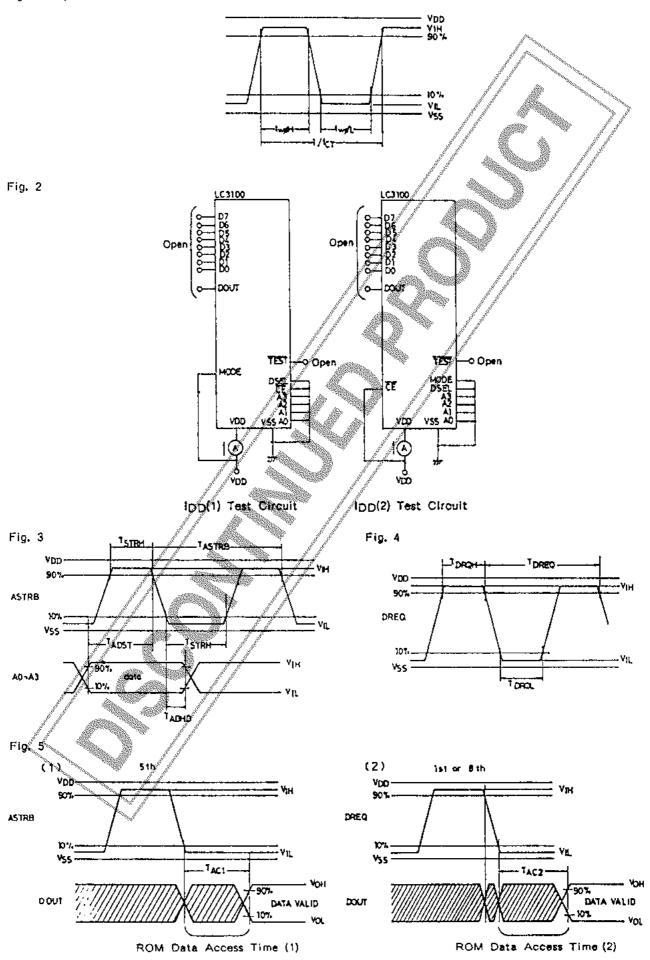


Note) Connect signals shown with dotted lines as required.

.. ....

Absolute Maximum Ratings at Maximum Supply Voltage Input Voltage Output Voltag Output Current Allowable Power Dissipation Operating Temperature	VDD max VIN VOUT IO Pd max Topg			-0.3 to -0.3 to -2.0	to +7.0 VDD+0.3 VDD+0.3 V to +2.0 200 0 to +70	unit V V MA mW					
Storage Temperature	Tstg		// /	-55	to +125	· · · ·					
Allowable Operating Conditions at Ta=-30 to +70 °C, VDD=4.5 to 6.5V, VSS=0V											
Supply Voltage	V	Von de	uten	ТУР	max	unit					
Input 'H'-Level Voltage	VIH VDD	VDD pin All input pins other than D0 to D7	4,5 0.7VDD	\$\$\$.0 	6.5	v v					
Input 'L'-Level Voltage	VIL	All input pins other than D0 to D7		dir di	0.3VDD	٧					
Operating Clock Frequency	fcT	Fig. 1, Ta=-30 to +60 C	<b>150</b> /	//BOO	960	kHz					
Operating Clock 'H'-Level	twoH	Fig. 1	0.3	800	300	JJ\$					
Pulse Width	*119211		Appeter appear			μ.					
Operating Clock 'L'-Level	twøL	Fig. 1	0.47			sц					
Pulse Width			State of the state			<i>,</i>					
			P. A. C.								
			in.								
Electrical Characteristics at T	a=-30 to	-70 °C, VDD=4.5 to 6.5%, VSS=0V //	min	typ	max	unit					
input 'H'-Level Current	iн	VIN=VDØ/			1.0	Αu					
Input 'L'-Level Current	1IL	VIN=V\$\$	-1.0			Αц					
Output 'H'-Level Voltage	VOH	IOH0.3mA // V	DD-0.6			V					
Output 'L'-Level Voltage	VOL	IQ[=0.3mA			0.6	V					
Output OFF Leak Current	IOFF1	Vo-VDD, DO to D7, Dody pin			1.0	Αų					
	ioff2	Yo-Vss Do to D7, Dour pin	-1.0			Αų					
Input Pin Capacitance	Ci 🦯			5	10	рF					
Pull-up Resistance	Rup 🎢	TEST pin	20		1000	kΩ					
Current Dissipation	IDD(1/	At operating mode, 1CT=960kHz, Fig.			2.0	mA					
	IDD(2)	At nonoperating mode, Ta=-30 to +50	, C,		1.0	μA					
en e											
AC Characteristics at Ta=30	to +70 'C.	VDD=4.5 to 6.5V, VSS=0V, RL=200kΩ	. Cp×50p	F							
and the second s			mln	typ	max	unit					
Address Setup Time	TADS	r Fig. 3	0.3	_		քԱ					
Address Hold Time	TADH		0.3			มร					
ASTRB 'H'-Level Pulse Widt	h TsTR	1 ////	0.3			JJ\$					
ASTRB 'L'-Level Pulse Widt			0.3			μs					
DREQ 'H'-Level Pulse Width	TDRO	H-/	0.3			213					
DREQ 'L'-Level Pulse Width	TORC	Ľ	0,3			ટાદ					
ASTRB Pulse Duration	TAST		1.5			) S					
DREQ Pulse Duration	<b>∄</b> DRE		1,5			քա					
ROM Data Access Time (1)	_/JAC1	fCT=200kHz typ.,Fig.5,Note 1	26,0			វាខ					
ROM Data Access Time (2)	//TAC2		26.0			រដ					
DREQ TO DOUT Delay Tim			0.6			StX					
DSEL TO D0-3 Delay Time			0.3			թե					
Cycle Time	TCYC	LE fCT=200kHz typ.,Fig.8,Note 1	30.6			2U,					

Fig. 1 Input Waveform at CT Pin





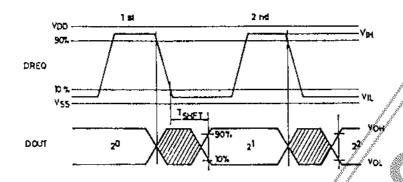


Fig. 7

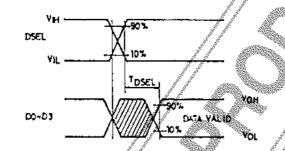
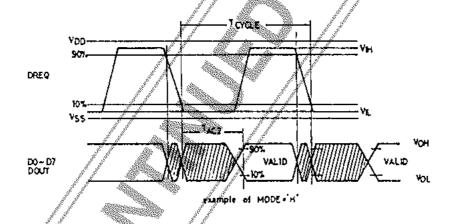


Fig. B



Note 1 Use the following formulas to calculate TAC max, Toycle max for a given for-